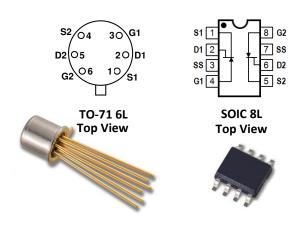


Over 30 Years of Quality Through Innovation

#### **Ultra-Low Noise Monolithic Dual N-Channel JFET Amplifier**

## **INDUSTRY'S FIRST 100% TESTED LOWEST NOISE JFET**

Absolute Maximum Ratings					
@ 25 °C (unless otherwise stated)					
Maximum Temperatures					
Storage Temperature	-65 to +150°C				
Junction Operating Temperature	-55 to +150°C				
Maximum Power Dissipation					
Continuous Power Dissipation @ +25°C	400mW				
Maximum Currents					
Gate Forward Current	$I_{G(F)} = 10mA$				
Maximum Voltages					
Gate to Source	$V_{\text{GSS}} = 40V$				
Gate to Drain	$V_{GDS} = 40V$				



#### **Features**

- Ultra-Low Noise: e<sub>n</sub> = 1.3nV/√Hz (typ), f = 1.0kHz and NBW = 1.0Hz
- Ultra-Low Noise: 1.5nV/√Hz (typ), f = 10Hz and NBW = 1.0Hz
- Tight Matching: IV<sub>GS1-2</sub>I = 15mV max
- High Breakdown Voltage: BV<sub>GSS</sub> = 40V max
- High Gain: Gfs = 20mS (typ)
- Low Capacitance: 25pF (typ)
- Improved Second Source Replacement for 2SK389

#### **Benefits**

- Improved System Noise Performance
- Unique Monolithic Dual Design Construction of Interleaving Both JFETs on the Same Piece of Silicon
- Excellent Matching and Thermal Tracking
- Great for Maximizing Battery
   Operated Applications by Providing a
   Wide Output Swing
- A High Signal to Noise Ratio as a Result of the LSK389's Low and Tightly Matched Gate Threshold Voltages

#### **Applications**

- · Audio Amplifiers and Preamps
- Discrete Low-Noise Operational Amplifiers
- Battery-Operated Audio Preamps
- Audio Mixer Consoles
- Acoustic Sensors
- Sonic Imaging
- Instrumentation Amplifiers
- Microphones
- Sonobouys
- Hydrophones
- Chemical and Radiation Detectors

#### Description

The LSK389 is the industry's lowest noise Dual N-Channel JFET, 100% tested, guaranteed to meet 1/f and broadband noise specifications, while eliminating burst (RTN or popcorn) noise entirely. The LSK389 Series, Monolithic Dual N-Channel JFETs were specifically designed to provide users a better performing, less time consuming and cheaper solution for obtaining tighter IDSS matching, and better thermal tracking, than matching individual JFETs. The LSK389 features four grades of IDSS: 2.6-6.5mA, 6.0-12.0mA, 10.0-20.0mA and 17-30mA, with an IDSS match of 10 percent, a gate threshold offset of 15mV, a voltage noise (en) of 1.3nV/√Hz typical at f = 1.0kHZ, with a Gain of 20mS typical, and 25pF of capacitance typical. The LSK389 provides a wide output swing, and a high signal

The LSK389 is the industry's lowest noise Dual N- to noise ratio as a result of the LSK389's tightly matched Channel JFET, 100% tested, guaranteed to meet 1/fand and low gate threshold voltages. The 40V breakdown broadband noise specifications, while eliminating burst (RTN provides maximum linear headroom in high transient or popcorn) noise entirely. The LSK389 Series, Monolithic program content amplifiers.

Additionally, the LSK389 provides a low input noise to capacitance product that has nearly zero popcorn noise. The narrow ranges of the IDSS electrical grades combined with the superior matching performance of the LSK389's monolithic dual construction promote ease of device tolerance in low voltage applications, as compared to matching single JFETs. Available in surface mount SOIC 8L and thru-hole TO-71 6L packages.

Contact the factory for tighter noise and other specification selections. For equivalent single N-Channel version, please refer to the LSK170 datasheet.

#### Electrical Characteristics @ 25°C (unless otherwise stated)

SYMBOL	CHARACTERISTIC		MIN	TYP	MAX	UNITS	CONDITIONS
$BV_{GSS}$	Gate to Source Breakdown Voltage		-40			V	$V_{DS} = 0$ , $I_D = -100 \mu A$
$V_{GS(OFF)}$	Gate to Source Pinch-off Voltage		-0.3		-1.6	V	$V_{DS} = 10V, I_D = 0.1 \mu A$
I <sub>DSS</sub>	Drain to Source Saturation Current	LSK389A	2.6		6.5	mA	$V_{DS} = 10V, V_{GS} = 0$
		LSK389B	6		12		
		LSK389C	10		20		
		LSK389D	17		30		
I <sub>GSS</sub>	Gate to Source Leakage Current			-100	-300	pА	$V_{GS} = -25V, V_{DS} = 0$
I <sub>G1G2</sub>	Gate to Gate Isolation Current			±1.0	±50	nA	$V_{G1^-G2} = \pm 45V, I_D = I_S = 0A$
G <sub>fs</sub>	Full Conduction Transconductance		8	20		mS	$V_{DS} = 10V, V_{GS} = 0, f = 1kHz$
e <sub>n</sub>	Noise Voltage			1.3	1.9	nV/√Hz	$V_{DS} = 10V$ , $I_D = 2mA$ , $f = 1kHz$ , NBW = 1Hz
e <sub>n</sub>	Noise Voltage			1.5	4.0	nV/√Hz	$V_{DS} = 10V$ , $I_{D} = 2mA$ , $f = 10Hz$ , $NBW = 1Hz$
C <sub>ISS</sub>	Common Source Input Capacitance			25		pF	$V_{DS} = 10V, V_{GS} = 0, f = 1MHz,$
C <sub>RSS</sub>	Common Source Reverse Transfer Cap.			5.5		pF	$V_{DG} = 10V, I_D = 0, f = 1MHz,$

#### Matching Characteristics @ 25°C (unless otherwise stated)

SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	CONDITIONS
$V_{\text{GS1}} - V_{\text{GS2}}$	Differential Gate to Source Cutoff Voltage		6.0	15	mV	$V_{DS} = 10V$ , $I_D = 1mA$
IDSS1 IDSS2	Saturation Drain Current Ratio	0.9	1.0	1.1	n/a	$V_{DS} = 10V, V_{GS} = 0V$

#### **Notes**

- 1. Absolute maximum ratings are limiting values above which serviceability may be impaired.
- 2. Pulse Test: PW ≤ 300µs, Duty Cycle ≤ 3%
- 3. All characteristics MIN/TYP/MAX numbers are absolute values. Negative values indicate electrical polarity only. Information furnished by Linear Integrated Systems is believed to be accurate and reliable. However, no responsibility is assumed for its use; nor for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of Linear Integrated Systems.

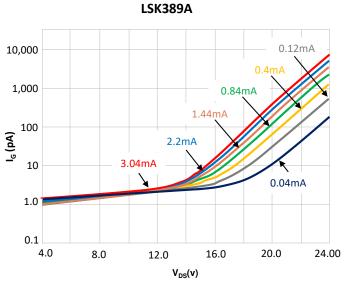


Figure 1. Gate Current ( $I_G$ ) vs.  $V_{DS}$  vs.  $I_D$ 

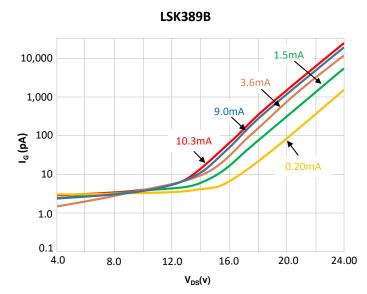
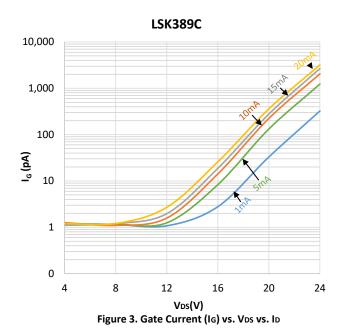
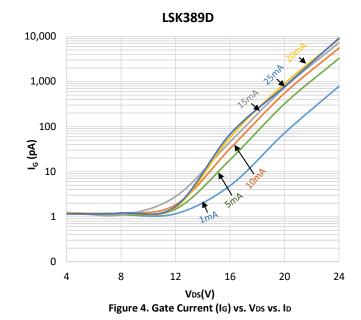


Figure 2. Gate Current (I<sub>G</sub>) vs. V<sub>DS</sub> vs. I<sub>D</sub>





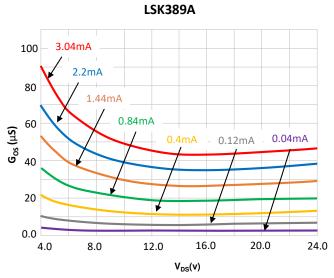


Figure 5. Output Conductance -  $\mathbf{G}_{\mathrm{OS}}$  vs.  $\mathbf{V}_{\mathrm{DS}}$  vs.  $\mathbf{I}_{\mathrm{D}}$ 

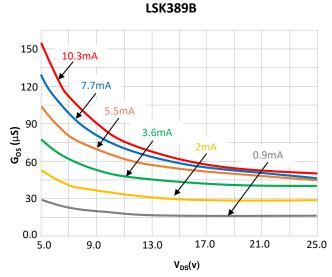
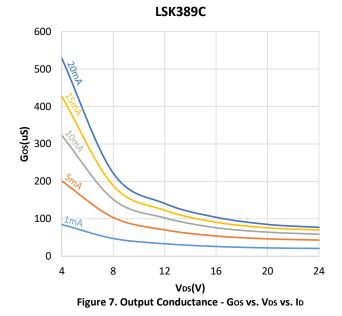
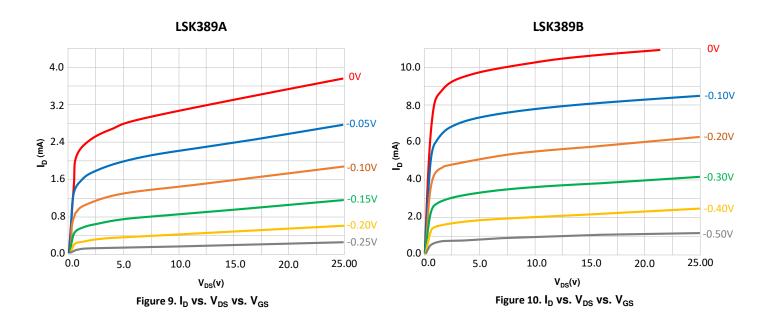
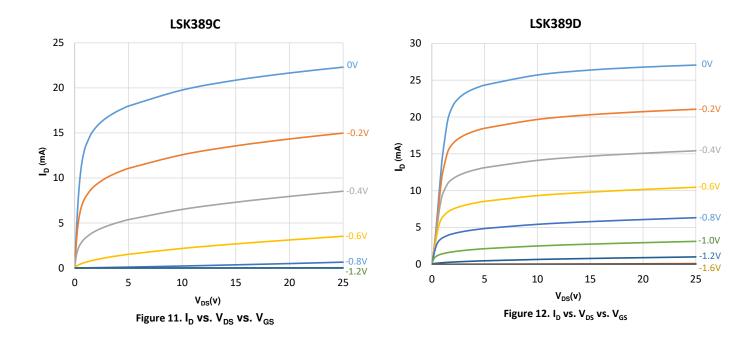


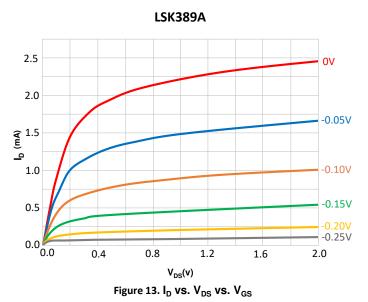
Figure 6. Output Conductance -  $G_{OS}$  vs.  $V_{DS}$  vs.  $I_{D}$ 

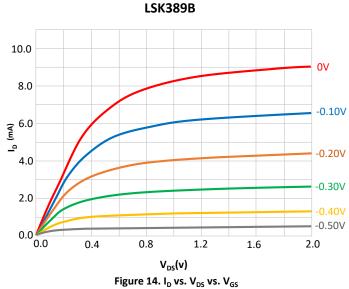


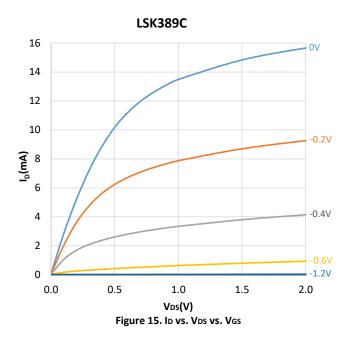
LSK389D 900 800 700 600 (**Sn**)so**9** 400 300 200 100 0 8 12 16 20 24 4 Vos(V) Figure 8. Output Conductance - Gos vs. VDs vs. ID

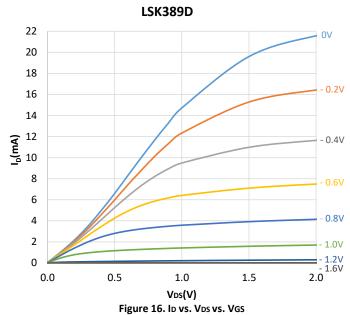






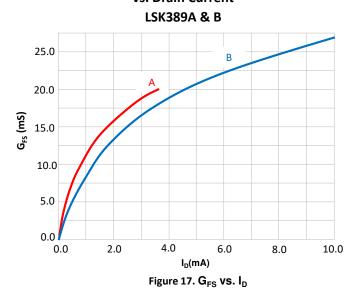




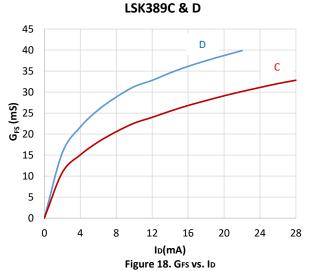


## **Typical Characteristics**

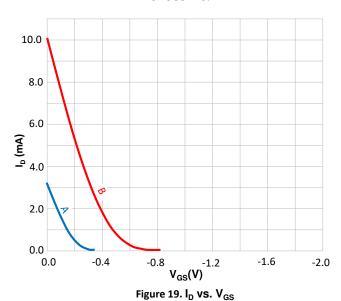
# Common Source Forward Transconductance vs. Drain Current



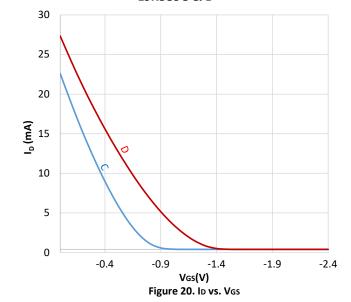
# Common Source Forward Transconductance vs. Drain Current



#### LSK389A & B



#### LSK389C & D



## **Typical Characteristics**

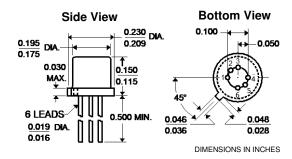
#### **Drain Current Transconductance** vs. Gate-Source Cutoff Voltage 24 45 gfs @ VDS = 10V, VGS = 0V, f = 1 kHzgfs-Forward Transconductance(mS) IDSS @ VDS = 10V, VGS = 0V 1055 8f5 10 20 4 15 4. -.80 50 9

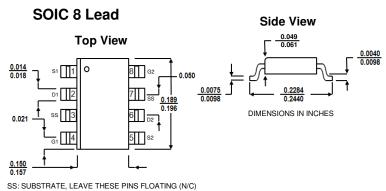
Figure 21.  $V_{GS}$  (cutoff) vs.  $I_{Dss}$  vs.  $G_{FS}$ 

#### **Equivalent Input Noise Voltage** vs. Frequency 2.0 VDS=10V en-Noise Voltage (nv/vHz) 1.8 ID=2mA 1.6 1.4 1.2 1.0 0.8 100 10 1,000 10,000 100,000 Figure 22. f - Frequency (Hz)

#### **Package Dimensions**

#### **TO-71 6 Lead**





## **Ordering Information**

## Standard Part Call-Out

LSK389A/B/C or D TO-71 6L RoHS

LSK389A/B/C or D SOIC 8L RoHS

#### **Custom Part Call-Out**

(Custom Parts Include SEL + 4 Digit Numeric Code)

LSK389A/B/C or D TO-71 6L RoHS SELXXXX

LSK389A/B/C or D SOIC 8L RoHS SELXXXX